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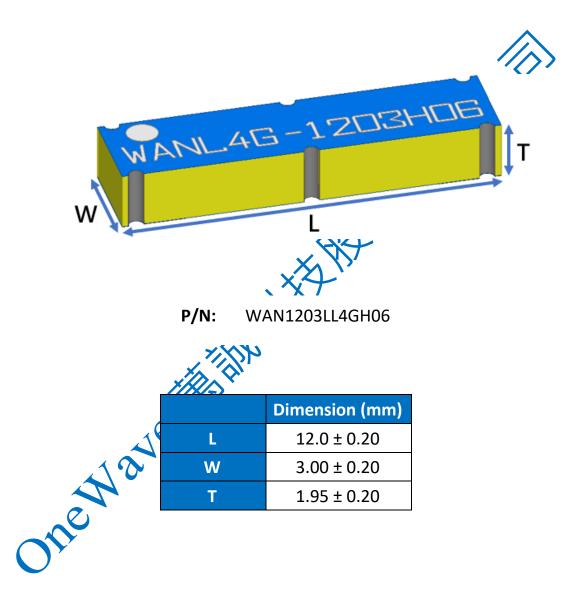
### OneWave Electronic Co., Ltd.

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# 1203 Chip antenna

For LTE Applications 824~960MHz & 1700~2700MHz



#### **Part Number Information**

	W	<u>AN</u>	<u>1203</u>	L	<u>L4G</u>	H	<u>06</u>		
Α		Α	В	С	D	Ε	F		
Γ	A	F	Product Seri	es		Antenna			
	B	Dimension W x L				12.0X3.0mm (+-0.2mm)			
	С	Material		High K material					
	D	Working Frequency			_	~960MHz 0~2700M			
	Ε	Feeding mode		Monopole	e & Single				
	F	Antenna type			1	ype = 06	SV		
e	ectrical Specification								
	Specification								

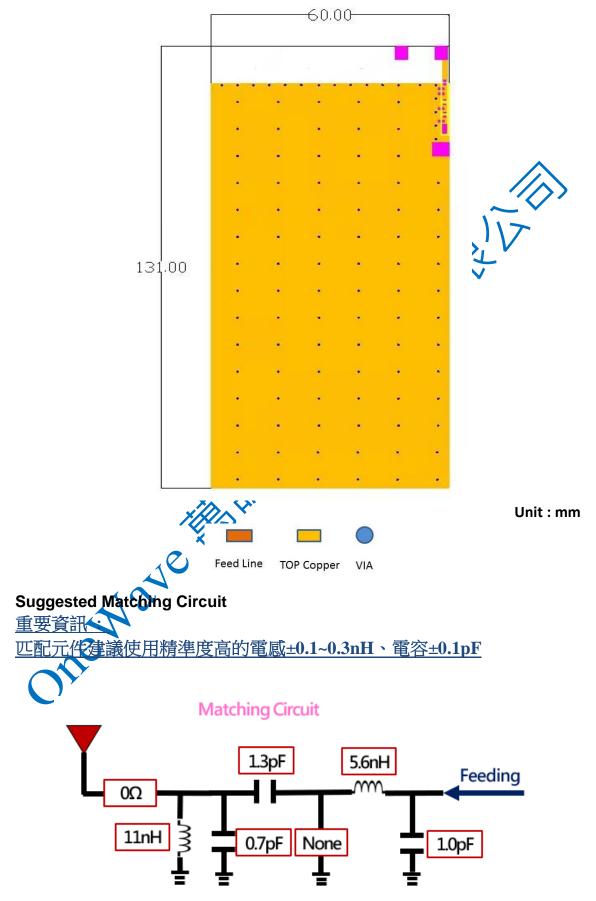
### **1. Electrical Specification**

Specification					
Part Number	WAN1203LL4GH06				
Central Frequency	824~960MHz & 1700~2700MHz	MHz			
Bandwidth	140 (Min.) / 1000 (Min.)	MHz			
Return Loss	-6(Max)	dB			
Peak Gain	2.85 / 1.87	dBi			
Impedance	50	Ohm			
Operating Temperature	-40~+110	°C			
Maximum Power	4	W			
Resistance to Soldering Heats	10 ( @ 260°C )	sec.			
Polarization	Linear				
Azimuth Beamwidth	Omni-directional				
Termination	Cu / Sn (Leadless)				

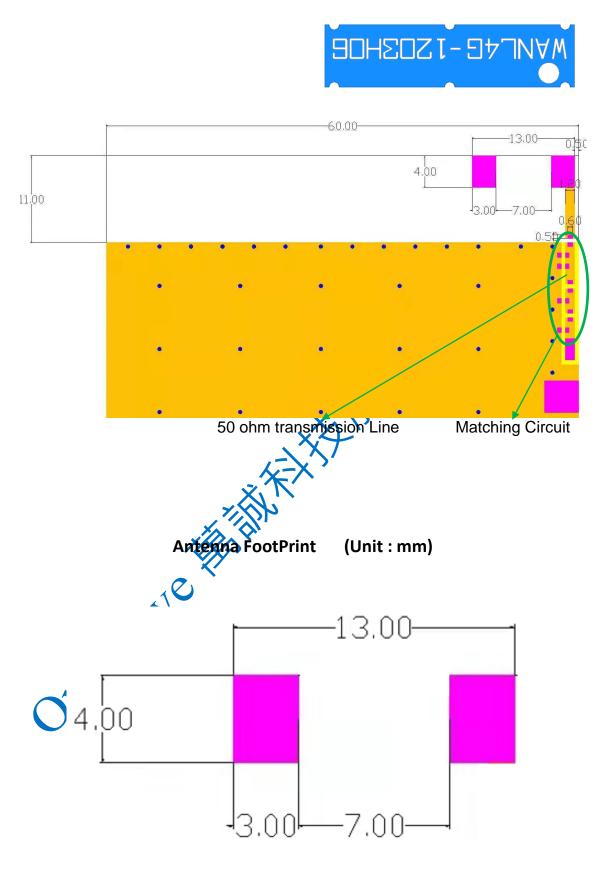
Remark : Bandwidth & Peak Gain was measured under evaluation board of next page

#### 2. Recommended PCB Pattern

#### 1. Evaluation Board Dimension

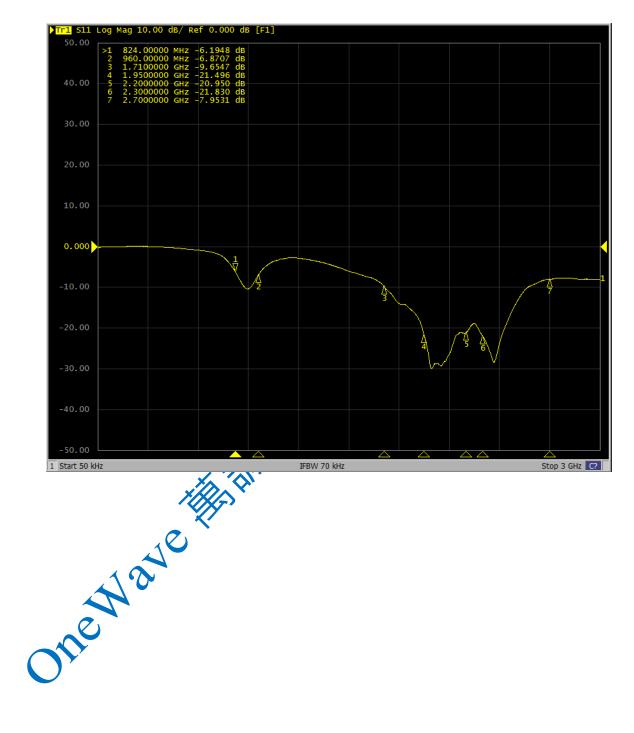


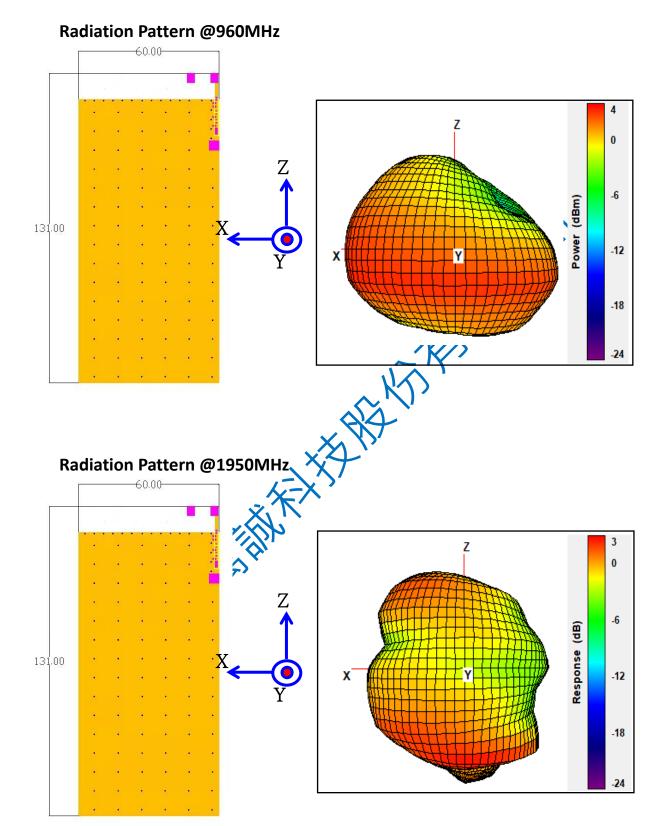
#### 1. Layout Dimensions in Clearance area(Size=60\*11mm)



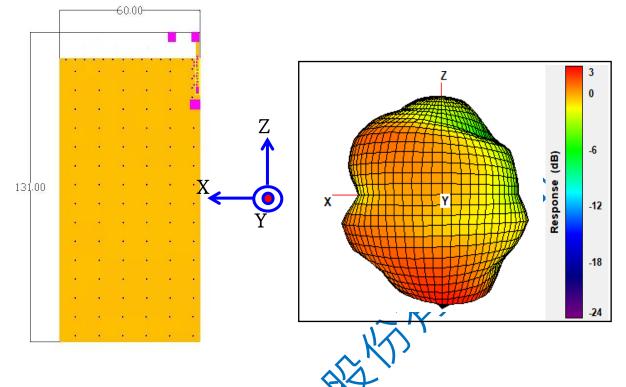
#### 3. Measurement Results

#### **Return Loss**





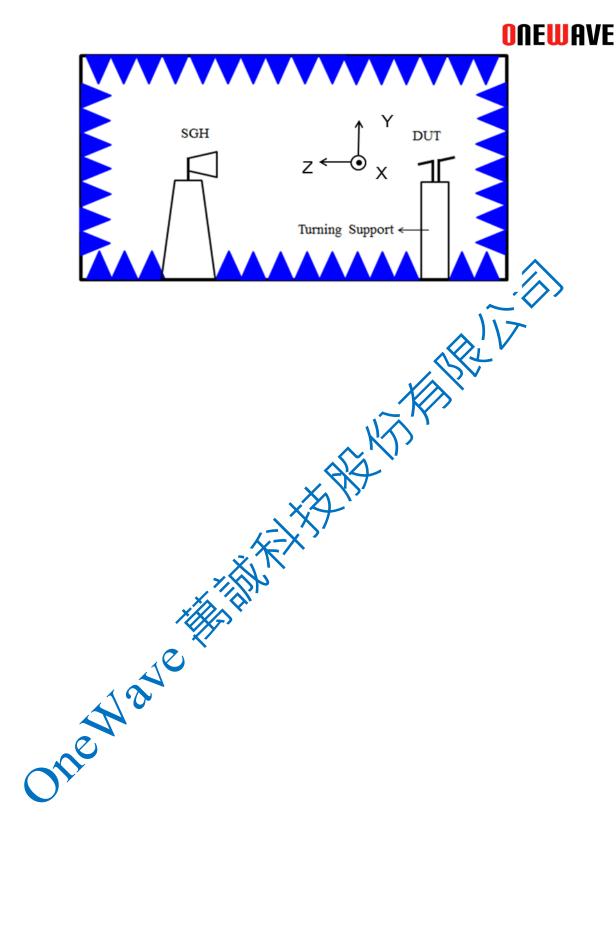




	AL			
		Efficiency	Peak Gain	Directivity
	824 MHz	66.76 %	X 2.72 dBi	4.47 dBi
	960 MHz	70.65 %	2.85 dBi	4.35 dBi
	1700 MHz	2.45 %	1.69 dBi	3.09 dBi
	1950 MHz	75.75 %	1.83 dBi	3.04 dBi
	2200 MHz	76.86 %	1.85 dBi	2.99 dBi
O'S	2300 MHz	75.59 %	1.87 dBi	3.08 dBi
	2700 MHz	73.98 %	1.84 dBi	3.14 dBi

Chamber Coordinate System

ONEWAVE TECHNOLOGY CO., LTD.





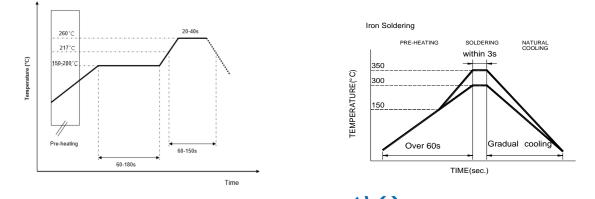
### 4.Reliability and Test Condictions

ITEM	REQUIREMENTS	TEST CONDITION		
Solderability	1. Wetting shall exceed 90% coverage	Pre-heating temperature:150°C/60sec.		
· · · · · · · · · · · · · · · · · · ·	2. No visible mechanical damage	Solder temperature:230 $\pm$ 5 $^{\circ}$ C		
		Duration:4±1sec.		
	TEMP (℃)	Solder:Sn-Ag3.0-Cu0.5		
	230℃ 4±1 sec.	Flux for lead free: rosin		
	150°C			
	60sec			
Solder heat	1. No visible mechanical damage	Pre-heating temperature:150°C/60sec.		
Resistance	2. Central Freq. change :within ± 6%	Solder temperature:260±5°C		
	TEMP (°C)	Duration:10±0.5sec.		
	10+0 5 000	Solder:Sn-Ag3.0-Cu0.5		
	260°C 10±0.5 sec.	Flux for lead free: rosin		
	150°C			
	60sec			
		× ×		
Component	1. No visible mechanical damage	The device should be reflow		
Adhesion		soldered(280 $\pm$ 5 $^{\circ}$ C for 10sec.) to a tinned		
(Push test)		copper substrate A dynometer force		
		gauge should be applied the side of the		
		component. The device must with-ST-F 0.5 Kg without failure of the termination		
	$\sim N$	attached to component.		
Component	1. No visible mechanical damage	Insert 10cm wire into the remaining open		
Adhesion	$\sim \chi T$	eye bend ,the ends of even wire lengths		
(Pull test)		upward and wind together.		
		Terminal shall not be remarkably		
		damaged.		
Thermal shock	1. No visible mechanical damage	+110℃=>30±3min		
	2. Central Freq. change :within ±6%	-40°C=>30±3min		
	Phase Temperature( $^{\circ}C$ ) Time(min)	Test cycle:10 cycles		
		The chip shall be stabilized at normal		
	1 +110±5℃ 30±3	condition for 2~3 hours before		
	2 Room Within Temperature 3sec	measuring.		
	$3 -40\pm2^{\circ}C$ $30\pm3$			
	4 Temperature 3sec			
Resistance to	1. No visible mechanical damage	Temperature: +110±5℃		
High	2. Central Freq. change :within ±6%	Duration: 1000±12hrs		
Temperature		The chip shall be stabilized at normal		
	3. No disconnection or short circuit.	condition for 2~3 hours before		
		measuring.		
Resistance to	1. No visible mechanical damage	Temperature:-40±5℃		
Low	2. Central Freq. change :within ±6%	Duration: 1000±12hrs		
Temperature	3. No disconnection or short circuit.	The chip shall be stabilized at normal		
		condition for 2~3 hours before		
		measuring.		
Humidity	1. No visible mechanical damage	Temperature: 40±2℃		
	2. Central Freq. change :within ±6%	Humidity: 90% to 95% RH		
	3. No disconnection or short circuit.	Duration: 1000±12hrs		
		The chip shall be stabilized at normal		
		condition for 2~3 hours before		
		measuring.		

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#### **5.Soldering and Mounting**

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. The terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.



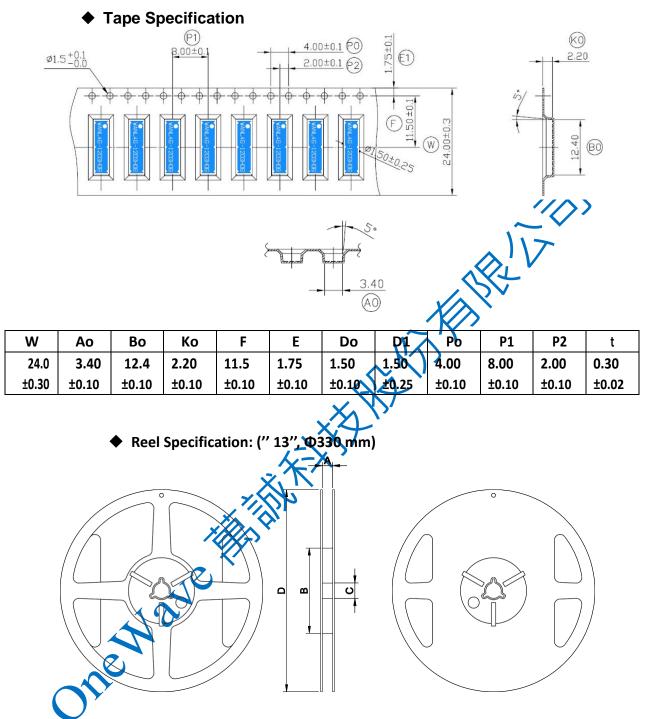
Recommended temperature profiles for re-flow soldering in Figure 1.

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150°C
- Never contact the ceraptic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- 280°C tip temperature (max)
- 1.0mm tip diameter (max)

Limit soldering time to 3 sec.

### 6.Packaging Information



13" x 24 mm

Tape Width(mm)	A(mm)	B(mm)	C(mm)	D(mm)	Chip/Reel(pcs)
24	24.6±0.5	99.5±1.0	13.5±0.5	330±1.0	850

#### 7. Storage and Transportation Information

#### **Storage Conditions**

To maintain the solderability of terminal electrodes:

- 1. Temperature and humidity conditions: -10~  $40^{\circ}$ C and 30~70% RH.
- 2. Recommended products should be used within 6 months from the time of delivery.
- 3. The packaging material should be kept where no chlorine or sulfur exists in the air.

#### **Transportation Conditions**

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- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.